





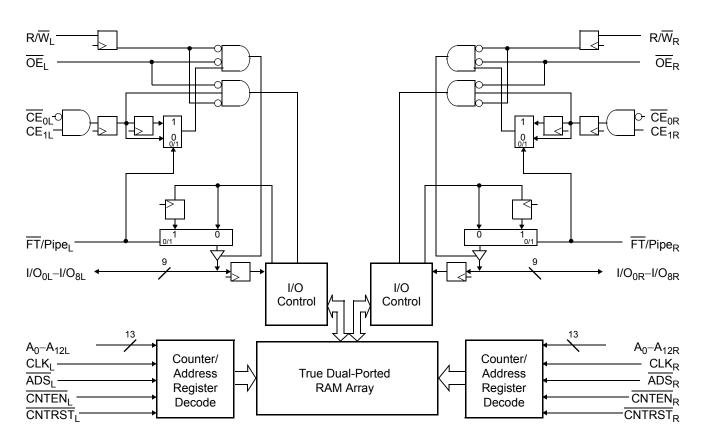
3.3-V 8 K × 9 Synchronous Dual Port Static RAM

Features

- True dual-ported memory cells which allow simultaneous access of the same memory location
- Flow-through/Pipelined device
 □ 8 K × 9 organization (CY7C09159AV)
- Three Modes
 - □ Flow-through
 - □ Pipelined
 - □ Burst
- Pipelined output mode on both ports allows fast 67-MHz operation
- 0.35-micron complementary metal oxide semiconductor (CMOS) for optimum speed/power
- High-speed clock to data access 9 ns (max.)

- 3.3 V Low operating power
 - ☐ Active = 135 mA (typical)
 - □ Standby = 10 μA (typical)
- Fully synchronous interface for easier operation
- Burst counters increment addresses internally
 - □ Shorten cycle times
 - □ Minimize bus noise
 - □ Supported in Flow-through and Pipelined modes
- Dual chip enables for easy depth expansion
- Automatic power-down
- Commercial temperature ranges
- Available in 100-pin thin quad plastic flatpack (TQFP)
- Pb-free packages available For a complete list of related documentation, click here.

Logic Block Diagram





Functional Description

The CY7C09159AV is a high-speed synchronous CMOS 8 K × 9 dual-port static RAM. Two ports are provided, permitting independent, simultaneous access for reads and writes to any location in memory. [1] Registers on control, address, and data lines allow for minimal setup and hold times. In pipelined output mode, data is registered for decreased cycle time. Clock to data valid $t_{CD2} = 9$ ns (pipelined). Flow-through mode can also be used to bypass the pipelined output register to eliminate access latency. In flow-through mode data will be available $t_{CD1} = 20$ ns after the address is clocked into the device. Pipelined output or flow-through mode is selected via the FT/Pipe pin.

Each port contains a burst counter on the input address register. The internal write pulse width is independent of the LOW- to-HIGH transition of the clock signal. The internal write pulse is self-timed to allow the shortest possible cycle times.

A HIGH on $\overline{\text{CE}}_0$ or LOW on CE_1 for one clock cycle will power down the internal circuitry to reduce the static power consumption. The use of multiple Chip Enables allows easier

banking of multiple chips for depth expansion configurations. In the pipelined mode, one cycle is required with CE_0 LOW and CE_1 HIGH to reactivate the outputs.

Counter enable inputs are provided to stall the operation of the address input and utilize the internal address generated by the internal counter for fast interleaved memory applications. A port's burst counter is loaded with the port's Address Strobe (ADS). When the port's Count Enable (CNTEN) is asserted, the address counter will increment on each LOW-to-HIGH transition of that port's clock signal. This will read/write one word from/into each successive address location until CNTEN is deasserted. The counter can address the entire memory array and will loop back to the start. Counter Reset (CNTRST) is used to reset the burst counter.

All parts are available in 100-pin thin quad plastic flatpack (TQFP) packages.

Note

^{1.} When simultaneously writing to the same location, final value cannot be guaranteed.



Contents

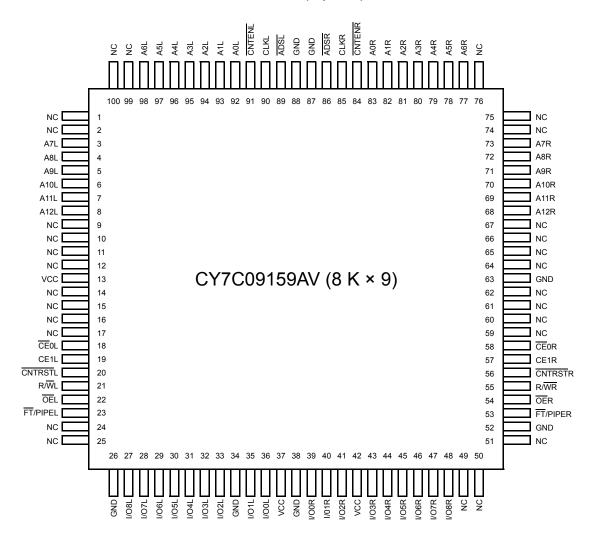
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Pin Configuration

100-Pin TQFP (Top View)



Selection Guide

	CY7C09159AV -9	Unit
f _{MAX2} (Pipelined)	67	MHz
Max access time (clock to data, pipelined)	9	ns
Typical operating current I _{CC}	135	mA
Typical standby current for I _{SB1} (Both ports TTL level)	20	mA
Typical standby current for I _{SB3} (Both ports CMOS level)	10	μΑ



Pin Definitions

Left Port	Right Port	Description
A _{0L} -A _{12L}	A _{0R} -A _{12R}	Address inputs (A ₀ –A ₁₂ for 8 K devices).
ADS _L	ADS _R	Address strobe input. Used as an address qualifier. This signal should be asserted LOW during normal read or write transactions. Asserting this signal LOW also loads the burst address counter with data present on the I/O pins.
CE _{0L} ,CE _{1L}	CE _{0R} ,CE _{1R}	Chip enable input. To select either the left or right port, both \overline{CE}_0 AND CE_1 must be asserted to their active states ($CE_0 \le V_{IL}$ and $CE_1 \ge V_{IH}$).
CLK _L	CLK _R	Clock signal. This input can be free-running or strobed. Maximum clock input rate is f _{MAX} .
CNTENL	CNTENR	Counter enable input. Asserting this signal LOW increments the burst address counter of its respective port on each rising edge of CLK. CNTEN is disabled if ADS or CNTRST are asserted LOW.
CNTRST _L	CNTRST _R	Counter <u>reset inp</u> ut. Asserting this signal LOW <u>rese</u> ts the <u>burst</u> address counter of its respective port to zero. CNTRST is not disabled by asserting ADS or CNTEN.
I/O _{0L} –I/O _{8L}	I/O _{0R} –I/O _{8R}	Data bus input/output (I/O ₀ -I/O ₈ for x9 devices).
ŌĒL	ŌĒ _R	Output enable input. This signal must be asserted LOW to enable the I/O data pins during read operations.
R/\overline{W}_L	R/W _R	Read/Write enable input. This signal is asserted LOW to write to the dual-port memory array. For read operations, assert this pin HIGH.
FT/PIPE _L	FT/PIPE _R	Flow-through/Pipelined select input. For flow-through mode operation, assert this pin LOW. For pipelined mode operation, assert this pin HIGH.
GND	•	Ground Input.
NC		No connect.
V _{CC}		Power input.

Maximum Ratings^[2]

Exceeding maximum ratings may shorten the useful life of the device. User guidelines are not tested.

Storage temperature	. –65 °C to +150 °C
Ambient temperature with power applied	.–55 °C to +125 °C
Supply voltage to ground potential	–0.5 V to +4.6 V
DC voltage applied to outputs in High Z state	–0.5 V to V _{CC} +0.5 V
DC input voltage	–0.5 V to V _{CC} +0.5 V
Output current into outputs (LOW)	20 mA
Static discharge voltage	>2001 V
Latch-up current	>200 mA

Operating Range

Range	Ambient Temperature	V _{CC}
Commercial	0 °C to +70 °C	3.3 V ± 300 mV

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Note
2. The voltage on any input or I/O pin can not exceed the power pin during power-up



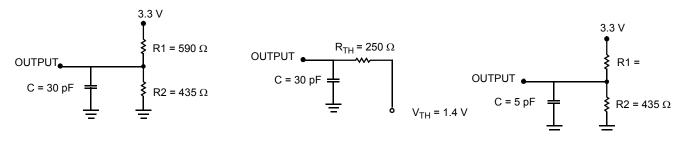
Electrical Characteristics Over the Operating Range

		CY	7C09159	AV		
Parameter	Description		Unit			
			Min	Тур	Max	-
V _{OH}	Output HIGH voltage (V _{CC} = Min., I _{OH} = -4.0 mA)		2.4	_	-	V
V _{OL}	Output LOW voltage (V _{CC} = Min., I _{OH} = +4.0 mA)		-	_	0.4	V
V _{IH}	Input HIGH voltage		2.0	-	_	V
V _{IL}	Input LOW voltage		_	-	0.8	V
I _{OZ}	Output leakage current	-10	_	10	μΑ	
I _{CC}	Operating current (V _{CC} = Max., I _{OUT} = 0 mA)	_{OUT} = 0 mA) Commercial	_	135	230	mA
	outputs disabled	Industrial		_		mA
I _{SB1} ^[3]	Standby current (Both ports TTL level)	Commercial	_	20	75	mA
	$CE_L \& CE_R \ge V_{IH}, f = f_{MAX}$	Industrial				mA
I _{SB2} ^[3]	Standby current (One port TTL level)	Commercial	_	95	155	mA
	$CE_L \mid CE_R \ge V_{IH}, f = f_{MAX}$	Industrial			_	mA
I _{SB3} ^[3]	Standby current (Both ports CMOS level)	Commercial	_	10	500	μΑ
	CE_L and $CE_R \ge V_{CC} - 0.2 \text{ V, f} = 0$	Industrial			_	μΑ
I _{SB4} ^[3]	Standby current (One port CMOS level)	Commercial	-	85	115	mA
	$CE_L \mid CE_R \ge V_{IH}, f = f_{MAX}$	Industrial				mA

Capacitance

Parameter Description		Test Conditions	Max	Unit	
C _{IN}	Input capacitance	$T_A = 25 ^{\circ}\text{C}, f = 1 \text{MHz},$	10	pF	
C _{OUT}	Output capacitance	$V_{CC} = 3.3 \text{ V}$	10	pF	

AC Test Loads



(a) Normal Load (Load 1)

(b) Thévenin Equivalent (Load 1)

(c) Three-state Delay (Load 2) (Used for $t_{CKLZ},\,t_{OLZ},\,\&\,t_{OHZ}$ including scope and jig)

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Switching Characteristics Over the Operating Range

		CY7C0	9159AV		
Parameter	Description		-9	Unit	
		Min	Max		
f _{MAX1}	f _{Max} flow-through	_	40	MHz	
f _{MAX2}	f _{Max} pipelined	_	67	MHz	
t _{CYC1}	Clock cycle time – flow-through	25	_	ns	
t _{CYC2}	Clock cycle time – pipelined	15	_	ns	
t _{CH1}	Clock HIGH time – flow-through	12	_	ns	
t _{CL1}	Clock LOW time – flow-through	12	_	ns	
t _{CH2}	Clock HIGH time – pipelined	6	_	ns	
t _{CL2}	Clock LOW time – pipelined	6	_	ns	
t _R	Clock rise time	_	3	ns	
t _F	Clock fall time	_	3	ns	
t _{SA}	Address setup time	4	-	ns	
t _{HA}	Address hold time	1	-	ns	
t _{SC}	Chip enable setup time	4	_	ns	
t _{HC}	Chip enable hold time	1	_	ns	
t _{SW}	R/W setup time	4	_	ns	
t _{HW}	R/W hold time	1	_	ns	
t _{SD}	Input data setup time	4	_	ns	
t _{HD}	Input data hold time	1	_	ns	
t _{SAD}	ADS setup time	4	_	ns	
t _{HAD}	ADS hold time	1	_	ns	
t _{SCN}	CNTEN setup time	4	_	ns	
t _{HCN}	CNTEN hold time	1	_	ns	
t _{SRST}	CNTRST setup time	4	_	ns	
t _{HRST}	CNTRST hold time	1	_	ns	
t _{OE}	Output enable to data valid	_	10	ns	
t _{OLZ}	OE to Low Z	2	_	ns	
t _{OHZ}	OE to High Z	1	7	ns	
t _{CD1}	Clock to data valid - flow-through	_	20	ns	
t _{CD2}	Clock to data valid - pipelined	_	9	ns	
t _{DC}	Data output hold after clock HIGH	2	_	ns	
t _{CKHZ}	Clock HIGH to output high Z	2	9	ns	
t _{CKLZ}	Clock HIGH to output low Z	2	_	ns	
Port to Port Dela	ays	I	1	1	
t _{CWDD}	Write port clock high to read data delay	_	40	ns	
t _{ccs}	Clock to clock setup time	_	15	ns	
	1		1		



Switching Waveforms

Figure 1. Read Cycle for Flow-Through Output $(\overline{\text{FT}}/\text{PIPE} = \text{V}_{\text{IL}})^{[4, 5, 6, 7]}$

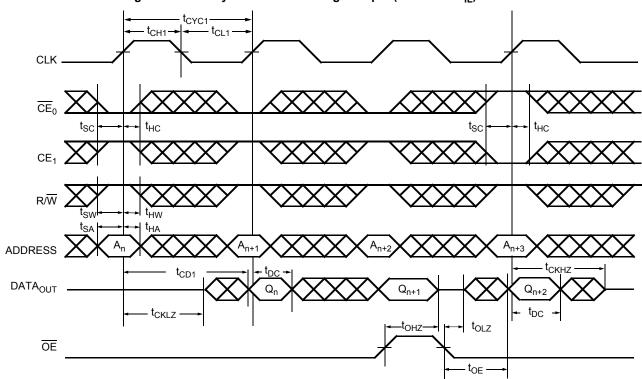
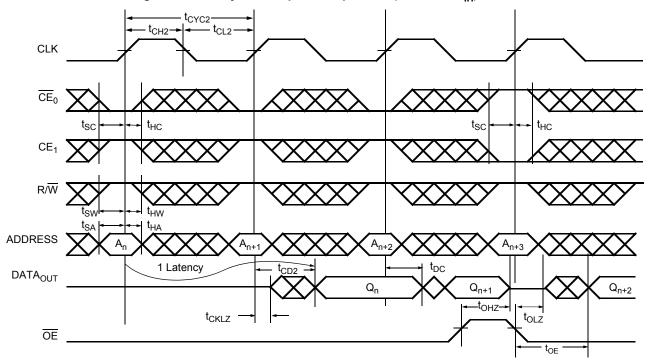


Figure 2. Read Cycle for Pipelined Operation ($\overline{\text{FT}}/\text{PIPE} = V_{\text{IH}}$)^[4, 5, 6, 7]



Notes

- A. OE is asynchronously controlled; all other inputs are synchronous to the rising clock edge.

 5. ADS = V_{IL}, CNTEN and CNTRST = V_{IH}

 6. The output is disabled (high-impedance state) by CE₀=V_{IH} or CE₁ = V_{IL} following the next rising edge of the clock.

 7. Addresses do not have to be accessed sequentially since ADS = V_{IL} constantly loads the address on the rising edge of the CLK. Numbers are for reference only.



Figure 3. Bank Select Pipelined Read^[8, 9]

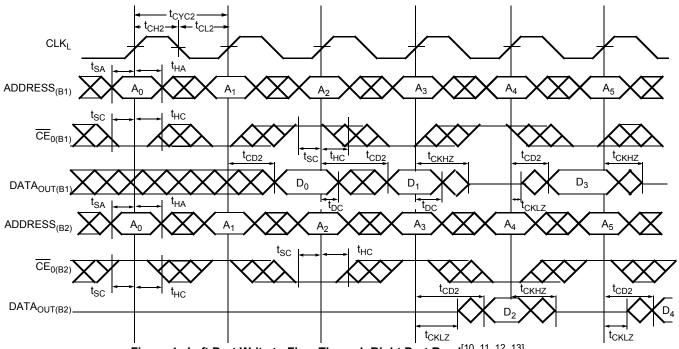
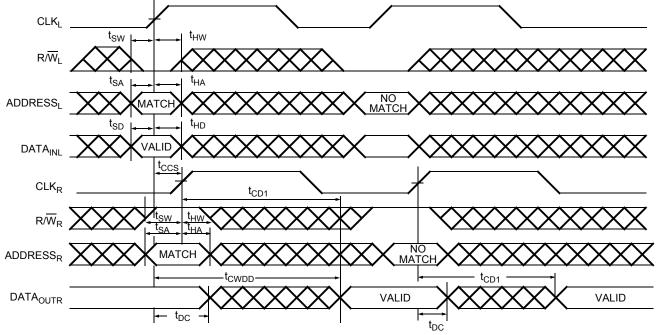


Figure 4. Left Port Write to Flow-Through Right Port Read^[10, 11, 12, 13]



Notes

- Notes
 8. In this depth expansion example, B1 represents Bank #1 and B2 is Bank #2; Each Bank consists of one Cypress dual-port device from this data sheet. ADDRESS_(B1) = ADDRESS_(B2).
 9. OE and ADS = V_{IL}; CE_{1(B1)}, CE_{1(B2)}, R/W, CNTEN, and CNTRST = V_{IH}.
 10. The same waveforms apply for a right port write to flow-through left port read.
 11. CE₀ and ADS = V_{IL}; CE₁, CNTEN, and CNTRST = V_{IH}.
 12. OE = V_{IL} for the right port, which is being read from. OE = V_{IH} for the left port, which is being written to.
 13. It t_{CCS} ≤ maximum specified, then data from right port READ is not valid until the maximum specified for t_{CWDD}. If t_{CCS}>maximum specified, then data is not valid until t_{CCS} + t_{CD1}. t_{CWDD} does not apply in this case.



Figure 5. Pipelined Read-to-Write-to-Read ($\overline{OE} = V_{IL}$)^[14, 15, 16, 17] t_{CL2} CLK **ADDRESS** $\mathsf{DATA}_{\mathsf{IN}}$ t_{CD2} t_{CKLZ} t_{CD2} t_{CKHZ} Q_{n} $\mathsf{Q}_{\mathsf{n+3}}$ NO OPERATION → WRITE Figure 6. Pipelined Read-to-Write-to-Read (OE Controlled)^[14, 15, 16, 17] τ_{CYC2} t_{CH2} t_{CL2} CLK t_{SW} t_{HW} **ADDRESS** $_{\tt t_{HD}}$ $\mathsf{DATA}_\mathsf{OUT}$ D_{n+2} t_{CD2} t_{CKLZ} t_{CD2} DATAIN $\mathsf{Q}_{\mathsf{n+4}}$ OE

14. Addresses do not have to be accessed sequentially since $\overline{ADS} = V_{IL}$ constantly loads the address on the rising edge of the CLK. Numbers are for reference only

WRITE

READ

- 15. Output state (HIGH, LOW, or High-Impedance) is determined by the previous cycle control signals.

 16. CE₀ and ADS = V_{IL}; CE₁, CNTEN, and CNTRST = V_{IH}.

 17. During "No operation," data in memory at the selected address may be corrupted and should be rewritten to ensure data integrity.

READ



Figure 7. Flow-Through Read-to-Write-to-Read ($\overline{OE} = V_{IL}$)[18, 19, 20, 21, 22]

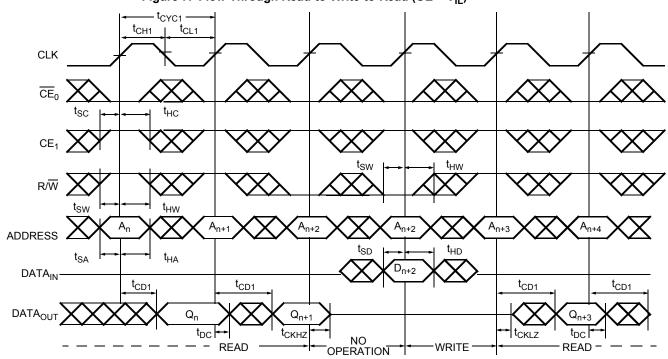
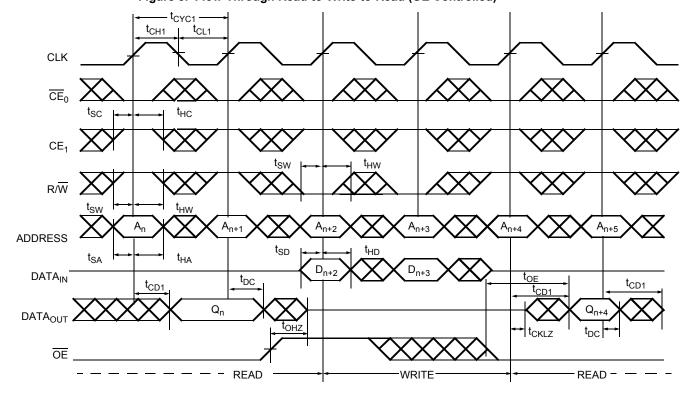


Figure 8. Flow-Through Read-to-Write-to-Read (OE Controlled)^[18, 19, 20, 21, 22]



- Notes

 18. ADS = V_{IL}, CNTEN and CNTRST = V_{IH}

 19. Addresses do not have to be accessed sequentially since ADS = V_{IL} constantly loads the address on the rising edge of the CLK. Numbers are for reference only 20. Output state (HIGH, LOW, or High-Impedance) is determined by the previous cycle control signals.

 21. CE₀ and ADS = V_{IL}; CE₁, CNTEN, and CNTRST = V_{IH}.

 22. During "No operation," data in memory at the selected address may be corrupted and should be rewritten to ensure data integrity.



Figure 9. Pipelined Read with Address Counter Advance^[23]

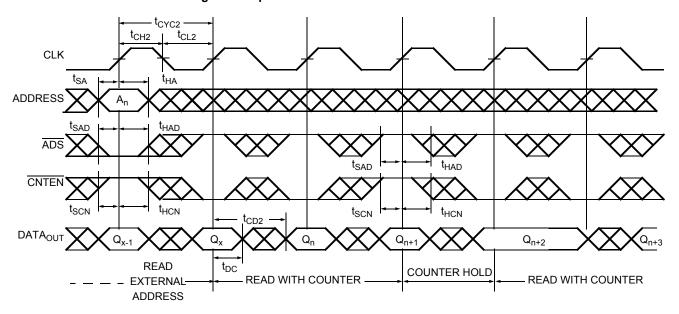


Figure 10. Flow-Through Read with Address Counter Advance^[23]

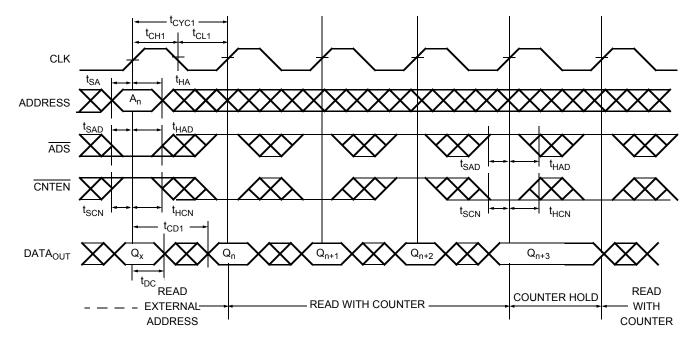
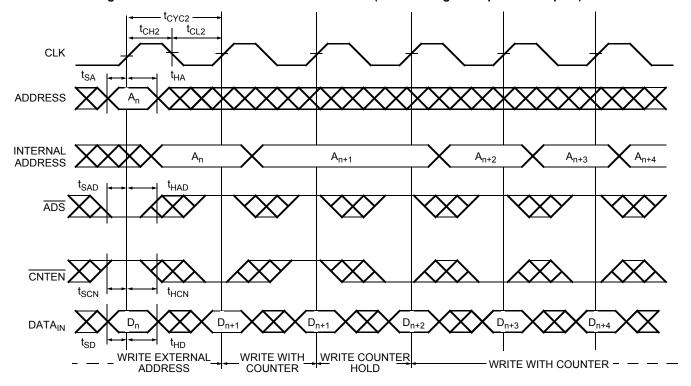




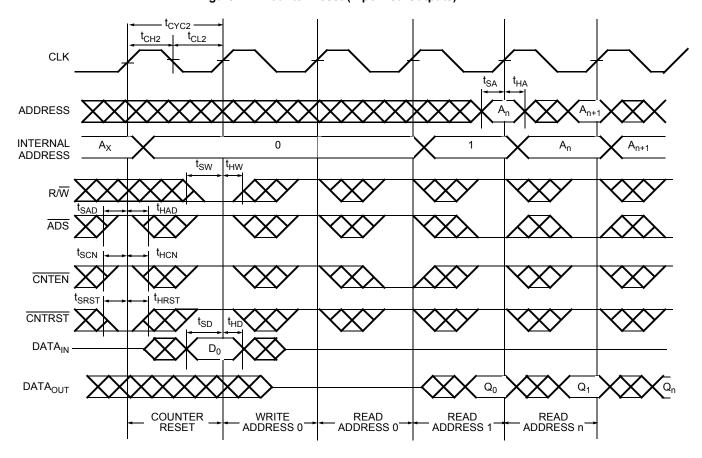
Figure 11. Write with Address Counter Advance (Flow-Through or Pipelined Outputs)[24, 25]



^{24.} CE₀ and R/W = V_{IL}; CE₁ and CNTRST = V_{IH}.
25. The "Internal Address" is equal to the "External Address" when ADS = V_{IL} and equals the counter output when ADS = V_{IH}.



Figure 12. Counter Reset (Pipelined Outputs)^[26, 27, 28, 29]



Notes

^{26.} Addresses do not have to be accessed sequentially since $\overline{ADS} = V_{IL}$ constantly loads the address on the rising edge of the CLK. Numbers are for reference only 27. Output state (HIGH, LOW, or High-Impedance) is determined by the previous cycle control signals.

28. $\overline{CE}_0 = V_{IL}$; $\overline{CE}_1 = V_{IH}$.

29. No dead cycle exists during counter reset. A READ or WRITE cycle may be coincidental with the counter reset.



Table 1. Read/Write and Enable Operation $^{[30,\ 31,\ 32]}$

		Inputs		Outputs		
OE	CLK	CE ₀	CE ₁	R/W	I/O ₀ –I/O ₉	Operation
Х		Н	Х	Х	High-Z	Deselected ^[33]
Х	7	Х	L	Х	High-Z	Deselected ^[33]
Х	7	L	Н	L	D _{IN}	Write
L	7	L	Н	Н	D _{OUT}	Read ^[33]
Н	Х	L	Н	Х	High-Z	Outputs disabled

Table 2. Address Counter Control Operation $^{[30,\ 34,\ 35,\ 36]}$

Address	Previous Address	CLK	ADS	CNTEN	CNTRST	I/O	Mode	Operation
Х	Х	7	X	Х	L	D _{out(0)}	Reset	Counter reset to address 0
A _n	Х	7	L	Х	Н	D _{out(n)}	Load	Address load into counter
X	A _n	7	Н	Н	Н	D _{out(n)}	Hold	External address blocked—counter disabled
Х	A _n	4	Н	L	Н	D _{out(n+1)}	Increment	Counter enabled—internal address generation

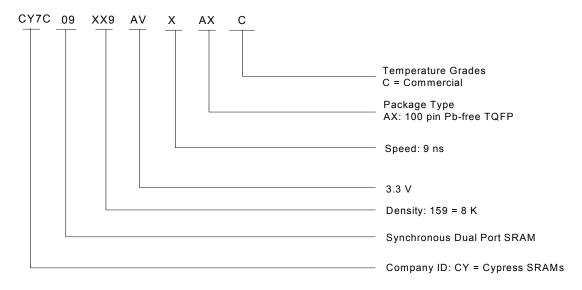


Ordering Information

Table 3. 8 K × 9 3.3-V Synchronous Dual-Port SRAM

Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range
9	CY7C09159AV-9AXC	A100	100-Pin Pb-free Thin Quad Flat Pack	Commercial

Ordering Code Definitions

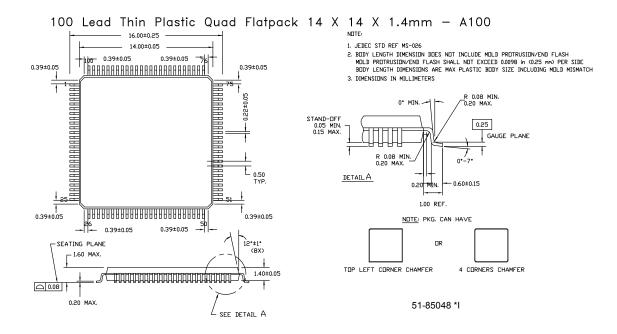




Package Diagram

Figure 13. 100-Pin TQFP (14 × 14 × 1.4 mm)

100 Lead Thin Plastic Quad Flatpack 14 X 14 X 1.4mm — A100



Acronyms

Acronym	Description	
CMOS	complementary metal oxide semiconductor	
TQFP	thin quad plastic flatpack	
I/O	input/output	
SRAM	static random access memory	

Document Conventions

Units of Measure

Symbol	Unit of Measure		
°C	degree Celsius		
MHz	megahertz		
μΑ	microampere		
mA	milliampere		
mV	millivolt		
ns	nanosecond		
Ω	ohm		
pF	picofarad		
V	volt		
W	watt		



Document History Page

Revision	ECN	Orig. of Change	Submission Date	Description of Change
**	110205	SZV	11/15/01	Change from Spec number: 38-00839 to 38-06053
*A	122303	RBI	12/27/02	Power up requirements added to Maximum Ratings Information
*B	393581	YIM	See ECN	Added Pb-Free Logo Added Pb-Free parts to ordering information: CY7C09159AV-9AXC, CY7C09159AV-12AXC, CY7C09169AV-12AXC, CY7C09169AV-12AXI
*C	2897159	RAME	03/22/10	Removed inactive parts from ordering information and updated package diagram.
*D	3076884	ADMU	11/02/10	Updated as per latest template Added Acronyms and Units of Measure table Added Ordering Code Definitions.
*E	3432711	ADMU	11/08/11	Updated template according to current CY standards. Removed information on CY7C09169AV. Removed speed bin –12. Updated package diagram.
*F	4575241	ADMU	11/19/2014	Added related documentation hyperlink in page 1. Updated Figure 13 in Package Diagram (spec 51-85048 *E to *I).



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